

**Notice of References Cited**

Application/Control No.

10/047,280

Applicant(s)/Patent Under

Reexamination

YIP ET AL.

Examiner

Tanh Q. Nguyen

Art Unit

2182

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**NON-PATENT DOCUMENTS**

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A handwritten signature is written over a stylized oval. The signature appears to begin with 'D' and end with 'X'.